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2133

[Signature]

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LINDA E. HASTINGS

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IN THE UNITED STATES PATENT AND TRADEMARK
OFFICE

Inventor: Kazunori KISHIMOTO

Serial No.: 10/083,447

Filed: February 26, 2002

Title: **METHOD OF TESTING A SEMICONDUCTOR
INTEGRATED CIRCUIT AND METHOD AND
APPARATUS FOR GENERATING TEST PATTERNS**

Examiner: John P. Trimmings

Group Art Unit:2133

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT

S I R :

In response to the Office Action mailed on August 17, 2004, the period for responding thereto having been set to expire after November 17, 2004, please amend the subject application as follows: